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CCS L56

SJ

INDUSTRY STANDARD OF THE PEOPLE'S REPUBLIC OF CHINA

SJ 21382-2018

Ion implantation uniformity test method

离子注入均匀性测试方法

(English Translation)

Issued by: Ministry of Industry and Information Technology

Preview: page 1 of 3 shown, 8 in the full document. Complete English PDF, instant download:
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1 Foreword

SJ 21382-2018 is issued by Ministry of Industry and Information Technology.

The SJ prefix, without a suffix, marks a mandatory standard: within its scope, compliance is required.

The document runs to 8 pages in English translation.

2 Scope Preview

SJ 21382-2018 is filed under Chinese Standard Classification L56, in the field of electronic components and information technology.

This catalogue holds 1,191 other SJ standards without an ICS number.

In this catalogue, SJ standards carry edition years from 1965 to 2021.

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3 About this standard

Sector: Electronics Industry Standard

Issued by: Ministry of Industry and Information Technology

English translation: about 8 pages (approximate)

Chinese original: about 10,124 characters

4 Related standards

Standards on related subjects:

SJ/T 11890-2023 - Design requirement of energy conservation for LED displays

SJ/T 11891-2023 - Energy efficiency measurement method for LED displays

GB/T 35010.6-2018 - Semiconductor die products -- Part 6: Requirements for concerning thermal simulation

SJ 21381-2018 - Test method for time dependent dielectric breakdown (TDDB)

SJ 21380-2018 - Hot carrier effect test method

SJ 21379-2018 - Electromigration effect test method

5 Classification and status

Chinese Standard Classification (CCS): L 56

Prefix SJ: mandatory standard.

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